

# SINGLE RETRIGGERABLE MONOSTABLE MULTIVIBRATOR WITH SCHMITT-TRIGGER INPUTS

Check for Samples: SN74LVC1G123

# **FEATURES**

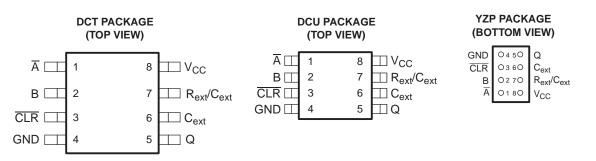
- Available in the Texas Instruments NanoFree<sup>™</sup> Package
- Supports 5-V V<sub>CC</sub> Operation
- Inputs Accept Voltages to 5.5 V
- Max t<sub>pd</sub> of 8 ns at 3.3 V
- Supports Mixed-Mode Voltage Operation on All Ports
- Schmitt-Trigger Circuitry on  $\overline{A}$  and B Inputs for **Slow Input Transition Rates**
- Edge Triggered From Active-High or Active-Low Gated Logic Inputs
- Retriggerable for Very Long Output Pulses, up • to 100% Duty Cycle
- **Overriding Clear Terminates Output Pulse**
- **Glitch-Free Power-Up Reset on Outputs**
- Ioff Supports Partial-Power-Down Mode Operation
- Latch-Up Performance Exceeds 100 mA Per JESD 78, Class II
- **ESD Protection Exceeds JESD 22** 
  - 2000-V Human-Body Model (A114-A)
  - 200-V Machine Model (A115-A)
  - 1000-V Charged-Device Model (C101)

# DESCRIPTION

The SN74LVC1G123 is a single retriggerable monostable multivibrator designed for 1.65-V to 5.5-V V<sub>CC</sub> operation.

This monostable multivibrator features output pulseduration control by three methods. In the first method, the A input is low, and the B input goes high. In the second method, the B input is high, and the  $\overline{A}$  input goes low. In the third method, the  $\overline{A}$  input is low, the B input is high, and the clear (CLR) input goes high.

The output pulse duration is programmed by selecting external resistance and capacitance values. The external timing capacitor must be connected between  $C_{ext}$  and  $R_{ext}/C_{ext}$  (positive) and an external resistor connected between Rext/Cext and V<sub>CC</sub>. To obtain variable pulse durations, connect an external variable resistance between Rext/Cext and V<sub>CC</sub>. The output pulse duration also can be reduced by taking CLR low



See mechanical drawings for dimensions.



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This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

### **DESCRIPTION (CONTINUED)**

Pulse triggering occurs at a particular voltage level and is not directly related to the transition time of the input pulse. The A and B inputs have Schmitt triggers with sufficient hysteresis to handle slow input transition rates with jitter-free triggering at the outputs.

Once triggered, the basic pulse duration can be extended by retriggering the gated low-level-active ( $\overline{A}$ ) or highlevel-active (B) input. Pulse duration can be reduced by taking CLR low. CLR can be used to override  $\overline{A}$  or B inputs. The input/output timing diagram illustrates pulse control by retriggering the inputs and early clearing.

This device is fully specified for partial-power-down applications using I<sub>off</sub>. The I<sub>off</sub> circuitry disables the outputs, preventing damaging current backflow through the device when it is powered down.

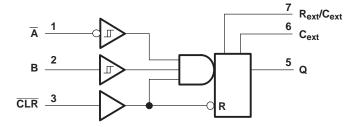
NanoFree<sup>™</sup> package technology is a major breakthrough in IC packaging concepts, using the die as the package.

	INPUTS		OUTPUTS
CLR	Ā	В	Q
L	Х	Х	L
х	Н	Х	L <sup>(1)</sup>
х	Х	L	L <sup>(1)</sup>
Н	L	<b>↑</b>	Л
Н	$\downarrow$	Н	Л
<b>↑</b>	L	Н	Л

### **FUNCTION TABLE**

 These outputs are based on the assumption that the indicated steady-state conditions at the A and B inputs have been set up long enough to complete any pulse started before the setup.

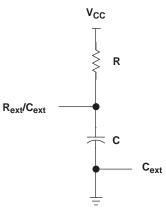
### Figure 1. LOGIC DIAGRAM (POSITIVE LOGIC)



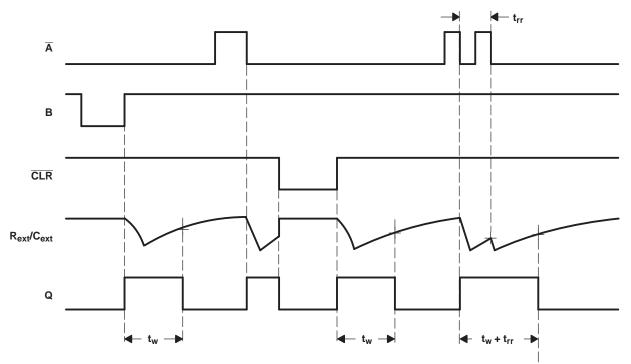


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# Figure 2. REQUIRED TIMING CIRCUIT







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### Absolute Maximum Ratings<sup>(1)</sup>

over operating free-air temperature range (unless otherwise noted)

			MIN	MAX	UNIT
$V_{CC}$	Supply voltage range		-0.5	6.5	V
VI	Input voltage range <sup>(2)</sup>		-0.5	6.5	V
Vo	Voltage range applied to any output in the	he high-impedance or power-off state <sup>(2)</sup>	-0.5	6.5	V
Vo	Voltage range applied to any output in t	he high or low state <sup>(2) (3)</sup>	-0.5	V <sub>CC</sub> + 0.5	V
I <sub>IK</sub>	Input clamp current	V <sub>1</sub> < 0		-50	mA
I <sub>OK</sub>	Output clamp current	V <sub>O</sub> < 0		-50	mA
I <sub>O</sub>	Continuous output current			±50	mA
	Continuous current through V <sub>CC</sub> or GNE	)		±100	mA
		DCT package		220	
$\theta_{JA}$	Package thermal impedance <sup>(4)</sup>	DCU package		227	°C/W
		YZP package		102	
T <sub>stg</sub>	Storage temperature range		-65	150	°C

(1) Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

(3) The value of  $V_{CC}$  is provided in the recommended operating conditions table.

(4) The package thermal impedance is calculated in accordance with JESD 51-7.



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# **Recommended Operating Conditions**<sup>(1)</sup>

			MIN	MAX	UNIT
V	Supply veltogo	Operating	1.65	5.5	V
V <sub>CC</sub>	Supply voltage	Data retention only	1.5		v
		$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$	$0.65 \times V_{CC}$		
V	Lligh lovel input voltage	$V_{CC}$ = 2.3 V to 2.7 V	1.7		V
VIH	High-level input voltage	$V_{CC} = 3 V$ to 3.6 V	2		v
		$V_{CC}$ = 4.5 V to 5.5 V	$0.7 \times V_{CC}$		
		$V_{CC} = 1.65 \text{ V to } 1.95 \text{ V}$		0.35 × V <sub>CC</sub>	
V		$V_{CC}$ = 2.3 V to 2.7 V		0.7	V
VIL	Low-level input voltage	$V_{CC} = 3 V \text{ to } 3.6 V$		0.8	v
		$V_{CC}$ = 4.5 V to 5.5 V		$0.3 \times V_{CC}$	
VI	Input voltage		0	5.5	V
Vo	Output voltage		0	V <sub>CC</sub>	V
		V <sub>CC</sub> = 1.65 V		-4	
		$V_{CC} = 2.3 V$		-8	
I <sub>OH</sub>	High-level output current			-16	mA
		$V_{CC} = 3 V$		-24	
		$V_{CC} = 4.5 V$		-32	
		V <sub>CC</sub> = 1.65 V		4	
		$V_{CC} = 2.3 V$		8	
I <sub>OL</sub>	Low-level output current			16	mA
		$V_{CC} = 3 V$		24	
		$V_{CC} = 4.5 V$		32	
D (2)	External timing registeres	$V_{CC} = 2 V$	5 k		Ω
R <sub>ext</sub> <sup>(2)</sup>	External timing resistance	$V_{CC} \ge 3 V$	1 k		Ω
T <sub>A</sub>	Operating free-air temperature		-40	125	°C

All unused inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, *Implications of Slow or Floating CMOS Inputs*, literature number SCBA004.
R<sub>ext</sub>/C<sub>ext</sub> is an I/O and must not be connected directly to GND or V<sub>CC</sub>.

# **Electrical Characteristics**

over recommended operating free-air temperature range (unless otherwise noted)

PA	RAMETER	TEST	CONDITIONS	V <sub>cc</sub>		C to 85°0 LVC1G12			°C to 125°C 4LVC1G123		UNIT
		-			MIN	TYP <sup>(1)</sup>	MAX	MIN	TYP <sup>(1)</sup>	MAX	_
		I <sub>OH</sub> = -100 μA		1.65 V to 5.5 V	V <sub>CC</sub> – 0.1			V <sub>CC</sub> – 0.1			
		$I_{OH} = -4 \text{ mA}$		1.65 V	1.2			1.2			
V <sub>OH</sub>		I <sub>OH</sub> = -8 mA		2.3 V	1.9			1.9			V
0.1	$I_{OH} = -16 \text{ mA}$ $I_{OH} = -24 \text{ mA}$			3 V	2.4			2.4			
				3 V	2.3			2.3			
		I <sub>OH</sub> = -32 mA		4.5 V	3.8			3.8			
		I <sub>OL</sub> = 100 μA		1.65 V to 5.5 V			0.1			0.1	
		$I_{OL} = 4 \text{ mA}$		1.65 V			0.45			0.45	
V <sub>OL</sub>		I <sub>OL</sub> = 8 mA		2.3 V			0.3			0.3	V
02		I <sub>OL</sub> = 16 mA		2.14			0.4			0.4	
		I <sub>OL</sub> = 24 mA		3 V			0.55			0.55	
		I <sub>OL</sub> = 32 mA		4.5 V			0.55			0.55	
	R <sub>ext</sub> /C <sub>ext</sub> <sup>(2)</sup>	B = GND,	$\overline{A} = \overline{CLR} = V_{CC}$	1.65 V to 5.5			±0.25			±0.25	
I <sub>I</sub>	Ā, B, CLR	$V_1 = 5.5 \text{ V or GND}$		V			±1			±1	μA
I <sub>off</sub>	<u>Ā, B,</u> Q, CLR	$V_1 \text{ or } V_0 = 5.5 \text{ V}$		0			±10			±10	μA
I <sub>cc</sub>	Quiescent	$V_I = V_{CC}$ or GND,	l <sub>O</sub> = 0	5.5 V			20			20	μA
				1.65 V			165			165	
				2.3 V			220			220	
I <sub>CC</sub>	Active state	$V_I = V_{CC}$ or GND,	$R_{ext}/C_{ext} = 0.5 V_{CC}$	3 V			280			280	μA
				4.5 V			650			650	
				5.5 V			975	· · ·		975	
CI	•	$V_I = V_{CC}$ or GND		3.3 V		3					pF

(1) All typical values are at  $V_{CC}$  = 3.3 V,  $T_A$  = 25°C. (2) This test is performed with the terminal in the off-state condition.

# **Timing Requirements**

over recommended operating free-air temperature range (unless otherwise noted) (see Figure 4)

	PARAMETER							C1G123 to 85°C					
			TEST CONDITIONS		V <sub>CC</sub> = 1.8 V ± 0.15 V		V <sub>CC</sub> = 2.5 V ± 0.2 V		V <sub>CC</sub> = 3.3 V ± 0.3 V		V <sub>CC</sub> = 5 V ± 0.5 V		UNIT
					MIN	TYP	MIN	TYP	MIN	TYP	MIN	TYP	
4 INI	Pulse duration	CLR			8		4		3		2.5		20
t <sub>w</sub> IN	Pulse duration	A or B trigger			8		4		3		2.5		ns
			P = 1 k 0	$C_{ext} = 100 \text{ pF}$						5.5		4.5	ns
	Dules retrigger time		$R_{ext} = 1 \ k\Omega$	$C_{ext} = 100 \ \mu F$						1.4		1.1	μs
t <sub>rr</sub>	Pulse retrigger time		R <sub>ext</sub> = 5 kΩ	$C_{ext} = 100 \text{ pF}$		75		45					ns
			$n_{ext} = 5 \text{ K}\Omega$	$C_{ext} = 100 \ \mu F$		1.8		1.4					μs



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### **Timing Requirements**

over recommended operating free-air temperature range (unless otherwise noted) (see Figure 4)

	PARAMETER								C1G123 o 125°C				
			TEST CONDITIONS		V <sub>CC</sub> = 1.8 V ± 0.15 V		V <sub>CC</sub> = 2.5 V ± 0.2 V		V <sub>CC</sub> = 3.3 V ± 0.3 V		V <sub>CC</sub> = 5 V ± 0.5 V		UNIT
					MIN	TYP	MIN	TYP	MIN	TYP	MIN	TYP	
t <sub>w</sub> IN	Pulse duration	CLR			8		4		3		2.5		20
L <sub>W</sub> IIN	Fuise duration	A or B trigger			8		4		3		2.5		ns
			R <sub>ext</sub> = 1 kΩ	$C_{ext} = 100 \text{ pF}$						5.5		4.5	ns
+	Pulse retrigger time			$C_{ext} = 100 \ \mu F$						1.4		1.1	μs
t <sub>rr</sub>	Fuise reingger inne		R <sub>ext</sub> = 5 kΩ	$C_{ext} = 100 \text{ pF}$		75		45					ns
			N <sub>ext</sub> = 5 K22	$C_{ext} = 100 \ \mu F$		1.8		1.4					μs

### **Switching Characteristics**

over recommended operating free-air temperature range, C<sub>L</sub> = 15 pF (unless otherwise noted) (see Figure 4)

				SN74LVC1G123 -40°C to 85°C									
PARAMETER	FROM (INPUT)	TO (OUTPUT)		<sub>c</sub> = 1.8 V 0.15 V		V <sub>CC</sub> = 2 ± 0.2		V <sub>CC</sub> = 3 ± 0.3		V <sub>CC</sub> = ± 0.5		UNIT	
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	MIN	MAX		
	Ā or B		7	18.5	52	4	17	3	11.5	2	7.6		
t <sub>pd</sub>	CLR	Q	5	12.4	34	3	11.5	2	8	1.5	5.5	ns	
	CLR trigger		7	17.4	54	4	15.5	3	10.5	2	7		

### **Switching Characteristics**

over recommended operating free-air temperature range, C<sub>L</sub> = 50 pF (unless otherwise noted) (see Figure 5)

								LVC1G C to 85					
PARAMETER	-	TO (OUTPUT)	TEST CONDITIONS		<sub>cc</sub> = 1.8 V ± 0.15 V	1	V <sub>CC</sub> = ± 0.		V <sub>CC</sub> = ± 0.		V <sub>CC</sub> = ± 0.5		UNIT
				MIN	TYP <sup>(1)</sup>	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
	Ā or B			6	18.6	57	3	18.5	2	12.5	1.5	8.2	
t <sub>pd</sub>	CLR	Q		4	11.6	36.5	2	12.5	1.5	8.6	1.5	6	ns
	CLR trigger			5	17.3	59	2.5	17	2	11.5	1.5	7.5	
			$C_{ext} = 28 \text{ pF},$ $R_{ext} = 2 \text{ k}\Omega$		225	600	190	220	170	200	150	180	ns
$t_w OUT^{(2)}$		Q	$\begin{array}{l} C_{ext} = 0.01 \ \mu\text{F}, \\ R_{ext} = 10 \ \text{k}\Omega \end{array}$		100	110	100	110	100	110	100	110	μs
			$\begin{array}{l} C_{ext} = 0.1 \ \mu\text{F}, \\ R_{ext} = 10 \ \text{k}\Omega \end{array}$		1	1.1	1	1.1	1	1.1	1	1.1	ms

(1)  $T_A = 25^{\circ}C$ (2)  $t_w =$  Duration of pulse at Q output

# **Switching Characteristics**

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over recommended operating free-air temperature range,  $C_L = 50 \text{ pF}$  (unless otherwise noted) (see Figure 5)

							-	LVC1G <sup>.</sup> C to 125					
PARAMETER		TO (OUTPUT)	TEST CONDITIONS		<sub>cc</sub> = 1.8 \ ± 0.15 V	1	V <sub>CC</sub> = ± 0.		V <sub>CC</sub> = ± 0.3		V <sub>CC</sub> = ± 0.		UNIT
				MIN	TYP <sup>(1)</sup>	MAX	MIN	MAX	MIN	MAX	MIN	MAX	
	A or B			6		58	3	19.5	2	13.2	1.5	8.7	
t <sub>pd</sub>	CLR	Q		4		37	2	13.5	1.5	9.2	1.5	6.5	ns
	CLR trigger			5		60	2.5	18	2	12	1.5	8	
			$C_{ext} = 28 \text{ pF},$ $R_{ext} = 2 \text{ k}\Omega$		225	600	190	220	170	200	150	180	ns
$t_w OUT^{(2)}$		Q	$\begin{array}{l} C_{ext} = 0.01 \ \mu\text{F}, \\ R_{ext} = 10 \ \text{k}\Omega \end{array}$		100	110	100	110	100	110	100	110	μs
			$\begin{array}{l} C_{ext} = 0.1 \ \mu\text{F}, \\ R_{ext} = 10 \ \text{k}\Omega \end{array}$		1	1.1	1	1.1	1	1.1	1	1.1	ms

(1)  $T_A = 25^{\circ}C$ (2)  $t_w =$  Duration of pulse at Q output

# **Operating Characteristics**

 $T_A = 25^{\circ}C$ 

	PARAMETER	TEST CONDITIONS		V <sub>CC</sub> = 1.8 V TYP	V <sub>CC</sub> = 2.5 V TYP	V <sub>CC</sub> = 3.3 V TYP	V <sub>CC</sub> = 5 V TYP	UNIT
6	Power dissipation	$\overline{A} = low, B = high,$	$R_{ext} = 1 k\Omega,$ No $C_{ext}$			35	37	٥F
C <sub>pd</sub>	capacitance	CLR = 10 MHz	$R_{ext} = 5 k\Omega,$ No $C_{ext}$	41	40			рг

# SN74LVC1G123

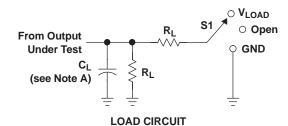
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# STRUMENTS

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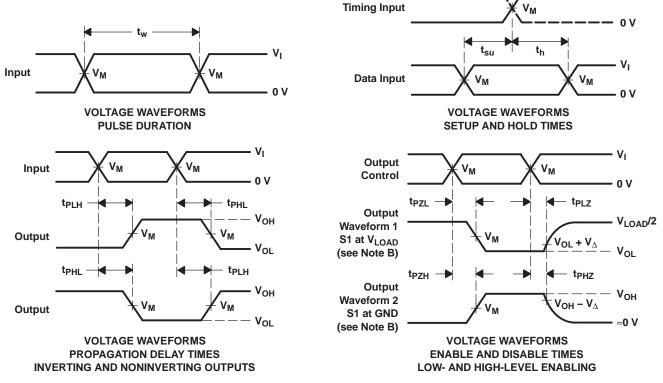
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### PARAMETER MEASUREMENT INFORMATION



TEST	S1
t <sub>PLH</sub> /t <sub>PHL</sub>	Open
t <sub>PLZ</sub> /t <sub>PZL</sub>	V <sub>LOAD</sub>
t <sub>PHZ</sub> /t <sub>PZH</sub>	GND

	INI	PUTS		N	•	-	
V <sub>cc</sub>	VI	t <sub>r</sub> /t <sub>f</sub>	V <sub>M</sub> V <sub>LOAD</sub>		CL	RL	$V_{\Delta}$
$1.8~V\pm0.15~V$	V <sub>CC</sub>	≤2 ns	V <sub>CC</sub> /2	$2 \times V_{CC}$	15 pF	<b>1 Μ</b> Ω	0.15 V
2.5 V $\pm$ 0.2 V	V <sub>CC</sub>	≤2 ns	V <sub>CC</sub> /2	$2 \times V_{CC}$	15 pF	<b>1 Μ</b> Ω	0.15 V
3.3 V $\pm$ 0.3 V	3 V	≤2.5 ns	1.5 V	6 V	15 pF	<b>1 Μ</b> Ω	0.3 V
5 V $\pm$ 0.5 V	V <sub>CC</sub>	≤2.5 ns	V <sub>CC</sub> /2	$2 \times V_{CC}$	15 pF	<b>1 Μ</b> Ω	0.3 V

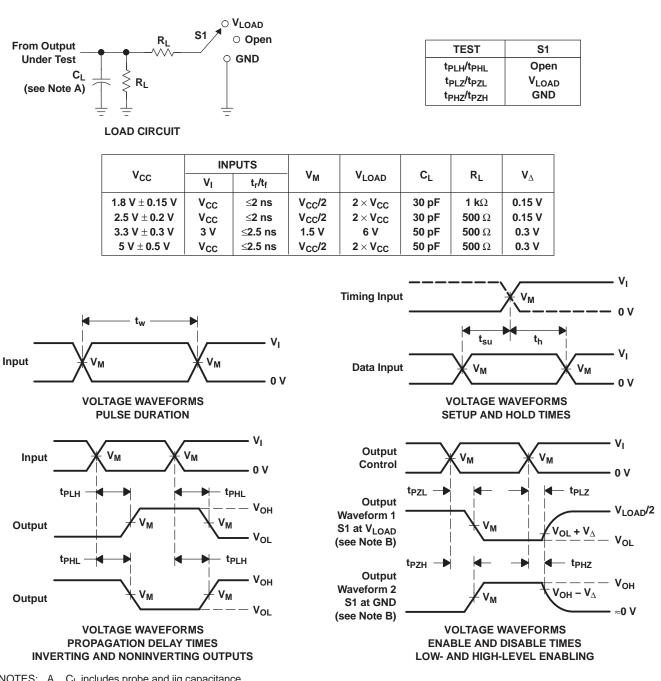


NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control. C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz, Z<sub>O</sub> = 50  $\Omega$ .
- D. The outputs are measured one at a time, with one transition per measurement.
- E.  $t_{PLZ}$  and  $t_{PHZ}$  are the same as  $t_{dis}$ .
- F. t<sub>PZL</sub> and t<sub>PZH</sub> are the same as t<sub>en</sub>.
- G. t<sub>PLH</sub> and t<sub>PHL</sub> are the same as t<sub>pd</sub>.
- H. All parameters and waveforms are not applicable to all devices.

### Figure 4. Load Circuit and Voltage Waveforms

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PARAMETER MEASUREMENT INFORMATION

NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control. C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz, Z<sub>O</sub> = 50  $\Omega$ .
- D. The outputs are measured one at a time, with one transition per measurement.
- E. t<sub>PLZ</sub> and t<sub>PHZ</sub> are the same as t<sub>dis</sub>.
- F. t<sub>PZL</sub> and t<sub>PZH</sub> are the same as t<sub>en</sub>.
- G. t<sub>PLH</sub> and t<sub>PHL</sub> are the same as t<sub>pd</sub>.
- H. All parameters and waveforms are not applicable to all devices.

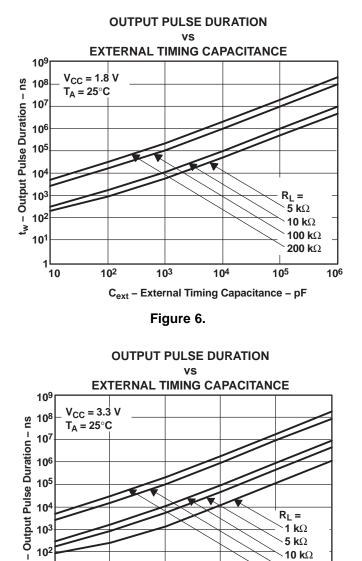
### Figure 5. Load Circuit and Voltage Waveforms



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### **APPLICATION INFORMATION**

Operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied.



**5 k**Ω

**10 k**Ω

**100 k**Ω

**200 k**Ω

1**0**6

10<sup>5</sup>

10

10

1 10

10<sup>2</sup>

10<sup>3</sup>

Figure 7.

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Cext - External Timing Capacitance - pF

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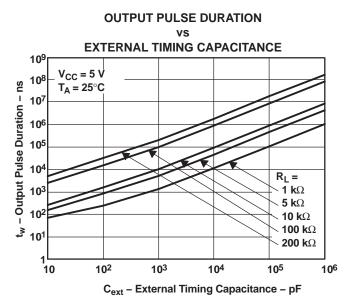


Figure 8.

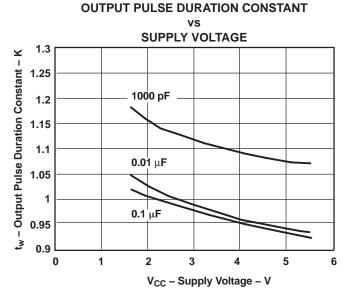


Figure 9.

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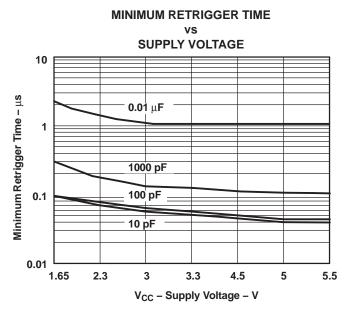


Figure 10.

# **REVISION HISTORY**

C	Changes from Revision B (January 2007) to Revision C Page									
•	Updated document to new TI datasheet format - no specification changes	. 1								
•	Removed Ordering Information table.	. 2								
•	Updated operating temperature range.	. 5								



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13-Jun-2014

# **PACKAGING INFORMATION**

Orderable Device	Status	Package Type	•	Pins	•	Eco Plan	Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
	(1)		Drawing		Qty	(2)	(6)	(3)		(4/5)	
74LVC1G123DCTRE4	ACTIVE	SM8	DCT	8	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	C23 Z	Samples
74LVC1G123DCTRG4	ACTIVE	SM8	DCT	8	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	C23 Z	Samples
74LVC1G123DCTTE4	ACTIVE	SM8	DCT	8	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	C23 Z	Samples
74LVC1G123DCTTG4	ACTIVE	SM8	DCT	8	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	C23 Z	Samples
74LVC1G123DCURE4	ACTIVE	US8	DCU	8	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	C23R	Samples
74LVC1G123DCURG4	ACTIVE	US8	DCU	8	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	C23R	Samples
74LVC1G123DCUTG4	ACTIVE	US8	DCU	8	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	C23R	Samples
SN74LVC1G123DCTR	ACTIVE	SM8	DCT	8	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	C23 Z	Samples
SN74LVC1G123DCTT	ACTIVE	SM8	DCT	8	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-1-260C-UNLIM	-40 to 125	C23 Z	Samples
SN74LVC1G123DCUR	ACTIVE	US8	DCU	8	3000	Green (RoHS & no Sb/Br)	CU NIPDAU   CU SN	Level-1-260C-UNLIM	-40 to 125	(C23Q ~ C23R)	Samples
SN74LVC1G123DCUT	ACTIVE	US8	DCU	8	250	Green (RoHS & no Sb/Br)	CU NIPDAU   CU SN	Level-1-260C-UNLIM	-40 to 125	(C23Q ~ C23R)	Samples
SN74LVC1G123YZPR	ACTIVE	DSBGA	YZP	8	3000	Green (RoHS & no Sb/Br)	SNAGCU	Level-1-260C-UNLIM	-40 to 85	(D87 ~ D8N)	Samples

<sup>(1)</sup> The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

**PREVIEW:** Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

<sup>(2)</sup> Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

**TBD:** The Pb-Free/Green conversion plan has not been defined.



13-Jun-2014

Pb-Free (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes. Pb-Free (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and package die adhesive used between the die adhesive

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

<sup>(3)</sup> MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

<sup>(4)</sup> There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

(5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.

(6) Lead/Ball Finish - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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# PACKAGE MATERIALS INFORMATION

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## TAPE AND REEL INFORMATION





# QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



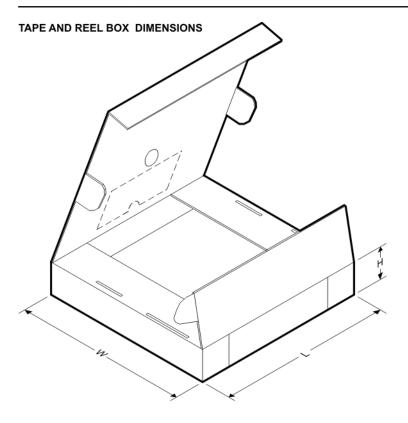
*All dimensions are nominal												
Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
74LVC1G123DCURG4	US8	DCU	8	3000	180.0	8.4	2.25	3.35	1.05	4.0	8.0	Q3
74LVC1G123DCUTG4	US8	DCU	8	250	180.0	8.4	2.25	3.35	1.05	4.0	8.0	Q3
SN74LVC1G123DCUR	US8	DCU	8	3000	180.0	8.4	2.25	3.35	1.05	4.0	8.0	Q3
SN74LVC1G123DCUR	US8	DCU	8	3000	178.0	9.5	2.25	3.35	1.05	4.0	8.0	Q3
SN74LVC1G123DCUT	US8	DCU	8	250	178.0	9.5	2.25	3.35	1.05	4.0	8.0	Q3
SN74LVC1G123YZPR	DSBGA	YZP	8	3000	178.0	9.2	1.02	2.02	0.63	4.0	8.0	Q1

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# PACKAGE MATERIALS INFORMATION

14-Nov-2014



\*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
74LVC1G123DCURG4	US8	DCU	8	3000	202.0	201.0	28.0
74LVC1G123DCUTG4	US8	DCU	8	250	202.0	201.0	28.0
SN74LVC1G123DCUR	US8	DCU	8	3000	202.0	201.0	28.0
SN74LVC1G123DCUR	US8	DCU	8	3000	202.0	201.0	28.0
SN74LVC1G123DCUT	US8	DCU	8	250	202.0	201.0	28.0
SN74LVC1G123YZPR	DSBGA	YZP	8	3000	220.0	220.0	35.0

# **MECHANICAL DATA**

MPDS049B - MAY 1999 - REVISED OCTOBER 2002

### DCT (R-PDSO-G8)

PLASTIC SMALL-OUTLINE PACKAGE



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion

D. Falls within JEDEC MO-187 variation DA.



DCT (R-PDSO-G8) PLASTIC SMALL OUTLINE Example Board Layout Example Stencil Design (Note C,E) (Note D) - 6x0,65 - 6x0,65 8x0,25-8x1,55 3,40 3,40 Non Solder Mask Defined Pad Example Pad Geometry -0,30 (Note C) 1,60 Example -0,07 Non-solder Mask Opening All Around (Note E) 4212201/A 10/11

NOTES: A. All linear dimensions are in millimeters.

- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



DCU (R-PDSO-G8)

PLASTIC SMALL-OUTLINE PACKAGE (DIE DOWN)



NOTES: A. All linear dimensions are in millimeters.

B. This drawing is subject to change without notice.

C. Body dimensions do not include mold flash or protrusion. Mold flash and protrusion shall not exceed 0.15 per side.

D. Falls within JEDEC MO-187 variation CA.



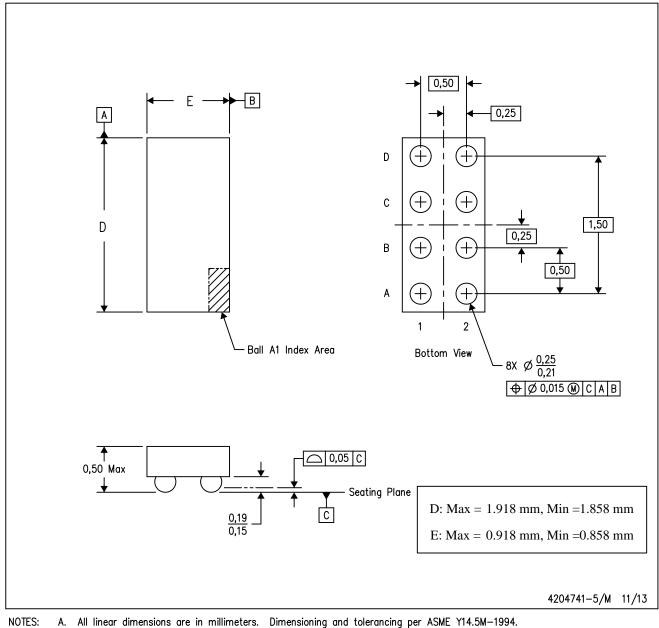


- NOTES: A. All linear dimensions are in millimeters. В. This drawing is subject to change without notice.
  - C. Publication IPC-7351 is recommended for alternate designs.
  - D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
  - E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



YZP (R-XBGA-N8)

DIE-SIZE BALL GRID ARRAY



- A. All linear dimensions are in millimeters. Dimension B. This drawing is subject to change without notice.
- C. NanoFree™ package configuration.

NanoFree is a trademark of Texas Instruments.



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